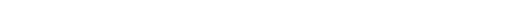


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<b>INFORMATION DISCLOSURE</b> <b>STATEMENT BY APPLICANT</b> <i>(use as many sheets as necessary)</i>					Application Number	
					Filing Date	Herewith
					First Named Inventor:	Stephen W. Smith
					Art Unit	2829
					Examiner Name	Kobert
Sheet	1	of	5	Attorney Docket Number	53470P020D	
<b>U.S. PATENT DOCUMENTS</b>						
Examiner Initials*	Cite No. <sup>1</sup>	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code <sup>2</sup> (if known)				
RK	—	us-	3,609,991	10/5/1971	Chu et al.	—
RK	—	us-	3,714,572	1/30/1973	Ham et al.	—
RK	—	us-	3,882,691	5/13/1975	Baines et al.	—
RK	—	us-	3,946,276	3/23/1976	Braun et al.	—
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RK	—	us-	4,104,700	8/1/1978	Hutchison et al.	—
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RK	—	us-	4,782,290	11/1/1998	Sakai et al.	—
RK	—	us-	4,791,983	12/20/1988	Nicol et al.	—
RK	—	us-	4,809,134	2/25/1989	Tustaniwskyj et al.	—
RK	—	us-	4,860,164	8/22/1989	Kaufman	—

Examiner Signature		Date Considered	9-13-04
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Sheet

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## Complete if Known

Application Number

Filing Date

Herewith

First Named Inventor:

Stephen W. Smith

Art Unit

2829

Examiner Name

Robert

Robert

Attorney Docket Number

53470P020D

## U.S. PATENT DOCUMENTS

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		Number-Kind Code <sup>2</sup> (if known)			
RK	—	US- 4,865,123	9/12/1989	Kawashima et al.	—
RK	—	US- 4,879,629	11/7/1989	Tustaniwskyj et al.	—
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RK	—	US- 6,449,741 B1	9/10/2002	Organ et al.	—
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## FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>8</sup>
		Country Code <sup>3</sup> Number <sup>4</sup> Kind Code <sup>5</sup> (if known)				

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# INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Complete if Known

Application Number

Herewith

Filing Date

Stephen W. Smith

First Named Inventor:

2829

Art Unit

Robert

Examiner Name

S3470P020D

Attorney Docket Number

## NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T <sup>2</sup>
RK	-	Wojciech Maly, "Current Testing," IEEE, 1990 International Test Conference, p. 257 (1990) <i>(No Month)</i>	/
RK	-	S. Wayne Bolinger and Scott F. Midkiff, "On Test Generation for IDDQ Testing of Bridging Faults in CMOS Circuits," IEEE, 1991 International Test Conference, pp. 598-607 (1991) <i>(No Month)</i>	/
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9-13-04

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# INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Sheet

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Completeness	
Application Number	
Filing Date	Herewith
First Named Inventor:	Stephen W. Smith
Art Unit	2829
Examiner Name	Robert

Attorney Docket Number

53470P020D

## NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T <sup>2</sup>
RK	-	Jerry M. Soden, Ronald R. Fritzmeier, and Charles F. Hawkins, "Zero Defects or Zero Stuck-At-Faults - CMOS IC Process Improvement, with IDDO," IEEE, 1990 International Test Conference, pp. 255-256 (1990) (No Month)	/
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RK	-	"Micromachine Technology," <a href="http://www.info.hqs.cae.ntt.jp/RD/ACT_act_3/micromachine.html">http://www.info.hqs.cae.ntt.jp/RD/ACT_act_3/micromachine.html</a> , 2 pages (prior to May 16, 2001)	/
RK	-	LTX MicroMaster Plus Brochure (Prior to May 16, 2001) (USA)	/
RK	-	LTX ValidMaster Plus Brochure (Prior to May 16, 2001) (USA)	/

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				Application Number		
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				First Named Inventor:		Stephen W. Smith
				Art Unit		2829
				Examiner Name	Robert	
Sheet	5	of	5	Attorney Docket Number	53470P020D	
<b>NON PATENT LITERATURE DOCUMENTS</b>						
Examiner Initials*	Cite No <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published				T <sup>2</sup>
RK	-	General Specifications, Class 388 and 283 Relays, <a href="http://magnecraft.com/page29.html">http://magnecraft.com/page29.html</a> , pgs. 1-2 (Wednesday, August 27, 1997)				/
RK	-	"General Purpose Square Base VDE Approved Relay," <a href="http://magnecraft.com/page33.html">http://magnecraft.com/page33.html</a> , pgs. 1-2 (Wednesday, August 27, 1997)				/
RK	-	LTX "Deltamaster Product Description," No. 999-7841-01-01, pp. 1-40 (LTX Corporation November 1992) (USA)				/
RK	-	"Fluorinert Liquid Heat Sink FC-3260," 3M New Product Announcement, January 1989				/
RK	-	Charles Wall, "Liquid Heat Sink Controls Computer Heat Flux," Reprinted from Electronic Packaging & Production (February 1989)				/
RK	-	Howard W. Markstein, "Liquid Cooling Optimizes Heat Transfer," Electronic Packaging and Production, pp. 46-49 (April 1988)				/
RK	-	Richard D. Danielson, Nick Krajewski, and Jerry Brost, "Cooling a Superfast Computer," Electronic Packaging and Production (July 1986)				/
RK	-	Ralph Remsburg, "New Routes to Cooler Electronics," Machine Design, pp. 73-76 (July 11, 1991)				/
RK	-	"Micromachined Relays," Teledyne Electronics and Communications, 1999. <i>(No Month)</i>				/
RK	-	J. Simon, S. Saffer, F. Sherman, and C.-J Kim, "Lateral Polysilicon Microrelays with a Mercury Micro-Drop Contact," pp. 1-15, 1998. <i>(Ab Month)</i>				/

Examiner Signature		Date Considered	9-13-04
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